

Prashant K Kulshreshtha

List of Publications by Year in descending order

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17
papers

194
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1478505

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18
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343
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| # | ARTICLE | IF | CITATIONS |
|----|--|------|-----------|
| 1 | Mechanistic Pathways for the Molecular Step Growth of Calcium Oxalate Monohydrate Crystal Revealed by In Situ Liquid-Phase Atomic Force Microscopy. ACS Applied Materials & Interfaces, 2021, 13, 37873-37882. | 8.0 | 5 |
| 2 | The effects of different types of additives on growth of biomineral phases investigated by in situ atomic force microscopy. Journal of Crystal Growth, 2019, 509, 8-16. | 1.5 | 7 |
| 3 | Characterization of film materials in wafer processing technology development by XPS. Journal of Electron Spectroscopy and Related Phenomena, 2019, 231, 57-67. | 1.7 | 2 |
| 4 | Direct observation of mineral-organic composite formation reveals occlusion mechanism. Nature Communications, 2016, 7, 10187. | 12.8 | 110 |
| 5 | Selective Laser Ablation in Resists and Block Copolymers for High Resolution Lithographic Patterning. Journal of Photopolymer Science and Technology = [Fotoporima Konwakai Shi], 2015, 28, 663-668. | 0.3 | 4 |
| 6 | Revealing beam-induced chemistry using modulus mapping in negative-tone EUV/e-beam resists with and without cross-linker additives. Proceedings of SPIE, 2015, , . | 0.8 | 1 |
| 7 | Harnessing entropic and enthalpic contributions to create a negative tone chemically amplified molecular resist for high-resolution lithography. Nanotechnology, 2014, 25, 315301. | 2.6 | 10 |
| 8 | Nanoscale modulus and surface chemistry characterization for collapse free resists. Proceedings of SPIE, 2013, , . | 0.8 | 3 |
| 9 | Sub-20nm lithography negative tone chemically amplified resists using cross-linker additives. Proceedings of SPIE, 2013, , . | 0.8 | 3 |
| 10 | Effect of nickel contamination on high carrier lifetime n-type crystalline silicon. Journal of Applied Physics, 2012, 111, 033702. | 2.5 | 6 |
| 11 | Nano-indentation: A tool to investigate crack propagation related phase transitions in PV silicon. Solar Energy Materials and Solar Cells, 2012, 96, 166-172. | 6.2 | 26 |
| 12 | Silicon PV Wafers: Mechanical Strength and Correlations with Defects and Stress. Solid State Phenomena, 2011, 178-179, 79-87. | 0.3 | 7 |
| 13 | Oxygen Precipitation Related Stress-Modified Crack Propagation in High Growth Rate Czochralski Silicon Wafers. Journal of the Electrochemical Society, 2011, 159, H125-H129. | 2.9 | 7 |
| 14 | Amorphization during Fracture of Thin Photovoltaic Silicon Wafers. ECS Transactions, 2010, 25, 49-55. | 0.5 | 1 |
| 15 | In-Situ Electrical Measurements of Thin Photovoltaic Silicon Wafers during Nanoindentation. ECS Transactions, 2010, 25, 41-48. | 0.5 | 0 |
| 16 | Crack Propagation in Large Diameter PV Silicon. ECS Transactions, 2010, 33, 25-32. | 0.5 | 2 |
| 17 | Evaluating Amorphization Around Micro-Cracks in PV Silicon. Materials Research Society Symposia Proceedings, 2009, 1210, 1. | 0.1 | 0 |